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# EIA
# STANDARD

EIA-61078

## Reality Block Diagrams

## EIA-61078
**(IEC 61078:2016, IDT)**

**January 2018**

**Electronic Components Industry Association**

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# RELIABILITY BLOCK DIAGRAMS

## FOREWORD

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This third edition cancels and replaces the second edition published in 2006. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

a) the structure of the document has been entirely reconsidered, the title modified and the content extended and improved to provide more information about availability, reliability and failure frequency calculations;
b) Clause 3 has been extended and clauses have been introduced to describe the electrical analogy, the "non-coherent" RBDs and the "dynamic" RBDs;
c) Annex B about Boolean algebra methods has been extended;
d) Annex C (Calculations of time dependent probabilities), Annex D (Importance factors), Annex E (RBD driven Petri net models) and Annex F (Numerical examples and curves) have been introduced.

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